

ABSTRACT OF THE DISCLOSUE

A WAFER LEVEL SYSTEM FOR PRODUCING BURN-IN/SCREEN, AND RELIABILITY EVALUATIONS TO BE PERFORMED ON ALL CHIPS SIMULTANEOUSLY WITHOUT ANY WAFER CONTACTING

A wafer level system for producing burn-in, voltages screen, and reliability evaluations which are to be performed on all wafers simultaneously without necessitating the probe contacting of any wafer during burn-in/stress. Also provided is a method for implementing the wafer level product burn-in/screen, and semiconductor

5 reliability evaluations on semiconductor chips pursuant to the wafer level system.

Pursuant to a preferred aspect all chips of a wafer are stressed simultaneously without having a probe physically contact any chip during the stress procedure. This concept can be applied to burn-in of product wafers, voltage screen of product wafers, and reliability evaluations of various failure mechanisms.

10